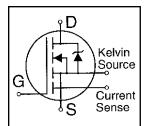
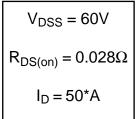


HEXFET® Power MOSFET

- Dynamic dv/dt Rating
- Current Sense
- 175°C Operating Temperature
- Fast Switching
- Ease of Paralleling
- Simple Drive Requirements

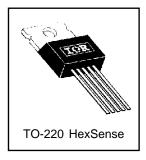




Description

Third Generation HEXFETs from International Rectifier provide the designer with the best combination of fast switching, ruggedized device, low on-resistance and cost-effectiveness.

The HEXSense device provides an accurate fraction of the drain current through the additional two leads to be used for control or protection of the device. These devices exhibit similar electrical and thermal characteristics as their IRF-series equivalent part numbers. The provision of a kelvin source connection effectively eliminates problems of common source inductance when the HEXSence is used as a fast, high-current switch in non current-sensing applications.



Absolute Maximum Ratings

	Parameter	Max.	Units
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V	50*	
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V	37	Α
I _{DM}	Pulsed Drain Current ①	210	
P _D @T _C = 25°C	Power Dissipation	150	W
	Linear Derating Factor	1.0	W/°C
V _{GS}	Gate-to-Source Voltage	±20	V
E _{AS}	Single Pulse Avalanche Energy ②	30	mJ
dv/dt	Peak Diode Recovery dv/dt ③	4.5	V/ns
TJ	Operating Junction and	-55 to + 175	
T _{STG}	Storage Temperature Range		℃
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	
	Mounting Torque, 6-32 or M3 screw	10 lbf•in (1.1 N•m)	

Thermal Resistance

	Parameter	Min.	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case	_	_	1.0	
R _{0CS}	Case-to-Sink, Flat, Greased Surface	_	0.50	_	°C/W
R _{0JA}	Junction-to-Ambient —	_	_	62	

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Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
V _{(BR)DSS}	Drain-to-Source Breakdown Voltage	60			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		0.060		V/°C	Reference to 25°C, I _D = 1mA
R _{DS(ON)}	Static Drain-to-Source On-Resistance			0.028	Ω	V _{GS} = 10V, I _D = 31A④
V _{GS(th)}	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
g fs	Forward Transconductance	18			S	$V_{DS} = 25V, I_D = 31A$
I _{DSS}	Drain-to-Source Leakage Current	_		25		$V_{DS} = 60V, V_{GS} = 0V$
1000	annio Cource Leakage Current			250		$V_{DS} = 48V, V_{GS} = 0V, T_{J} = 150^{\circ}C$
I _{GSS}	Gate-to-Source Forward Leakage			100		$V_{GS} = 20V$
·G55	Gate-to-Source Reverse Leakage			-100		$V_{GS} = -20V$
Qg	Total Gate Charge			95		I _D = 52A
Q _{qs}	Gate-to-Source Charge			27	nC	$V_{DS} = 48V$
Q _{gd}	Gate-to-Drain ("Miller") Charge			46		V _{GS} = 10V, See Fig. 6 and 13 @
t _{d(on)}	Turn-On Delay Time		19			$V_{DD} = 30V$
t _r	RiseTime		120			I _D = 52A
t _{d(off)}	Turn-Off Delay Time		55			$R_G = 9.1\Omega$
t _f	FallTime		86			$R_D = 0.54\Omega$, See Fig. 10 \oplus
L _D	Internal Drain Inductance		4.5		nH	Between lead, 6 mm (0.25in.) from package
L _c	Internal Source Inductance		7.5		11111	and center of die contact
C _{iss}	Input Capacitance		2500			V _{GS} = 0V
C _{oss}	Output Capacitance		1200		pF	$V_{DS} = 25V$
C _{rss}	Reverse Transfer Capacitance		200			f = 1.0MHz, See Fig. 5
r	Current Sensing Ratio	2460		2720		I _D = 52A, V _{GS} = 10V
Coss	Output Capacitance of Sensing Cells		9.0		pF	$V_{GS} = 0V, V_{DS} = 25V, f = 1.0MHz$

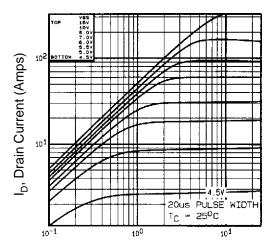
Source-Drain Ratings and Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions		
Is	Continuous Source Current	uous Source Current		50*		MOSFET symbol		
	(Body Diode)		— — s			showing the		
I _{SM}	Pulsed Source Current			040	040	040	Α	integral reverse
	(Body Diode) ①			210		p-n junction diode.		
V_{SD}	Diode Forward Voltage			2.5	V	T _J = 25°C, I _S = 52A, V _{GS} = 0V ④		
t _{rr}	Reverse Recovery Time		140	300	ns	$T_J = 25$ °C, $I_F = 52A$		
Q _{rr}	Reverse Recovery Charge		1.2	2.8	nC	di/dt = 100A/µs ④		
t _{on}	Forward Turn-On Time	Intri	Intrinsic turn-on time is negligible (turn-on is dominated by L _S +L _D)					

Notes:

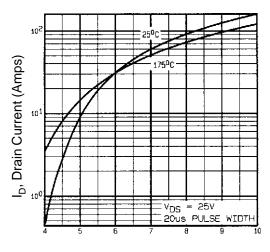
- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- $\ \Im \ I_{SD} \leq 52A, \ di/dt \leq 250A/\mu s, \ V_{DD} \leq V_{(BR)DSS}, \ T_{J} \leq 175^{\circ}C$
- $\begin{tabular}{ll} @V_{DD}=25V, \ starting \ T_J=25^{\circ}C, \ L=0.013mH \\ R_G=25\Omega, \ I_{AS}=52A. \ (See \ Figure \ 12) \\ \end{tabular}$
- 4 Pulse width $\leq 300 \mu s$; duty cycle $\leq 2\%$.

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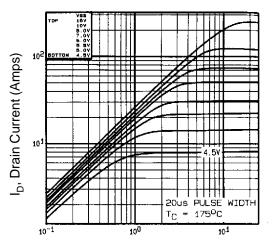
 V_{DS} , Drain-to-Source Voltage (Volts)

Fig. 1 Typical Output Characteristics, T_c =25°C



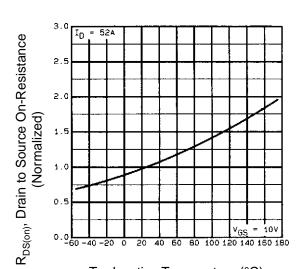
V_{DS}, Gate-to-Source Voltage (Volts)

Fig. 3 Typical Transfer Characteristics



V_{DS}, Drain-to-Source Voltage (Volts)

Fig. 2 Typical Output Characteristics, T_c =175°C

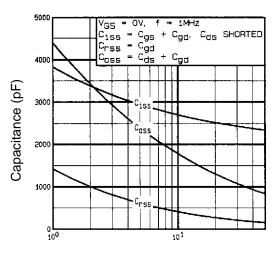


T_J, Junction Temperature (°C)

Fig. 4 Normalized On-Resistance vs. Temperature

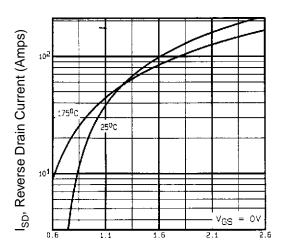
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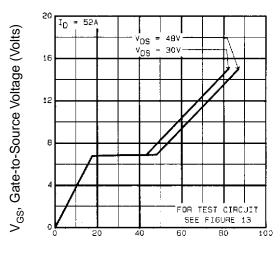
V_{DS}, Drain-to-Source Voltage (Volts)

Fig. 5 Typical Capacitance vs. Drain-to-Source Voltage



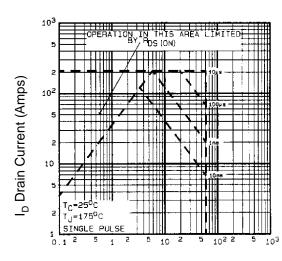
V_{SD}, Source-to-Drain Voltage (Volts)

Fig. 7 Typical Source-Drain Diode **Forward Voltage**



Q_G, Total Gate Charge (nC)

Fig. 6 Typical Gate Charge vs. Gate-to-Source Voltage



V_{DS}, Drain-to-Source Voltage (Volts)

Fig. 8 Maximum Safe Operating Area

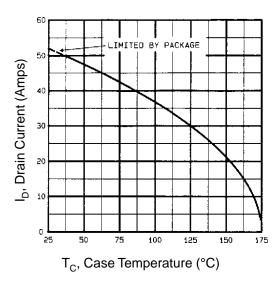


Fig. 9 Maximum Drain Current vs. Case Temperature

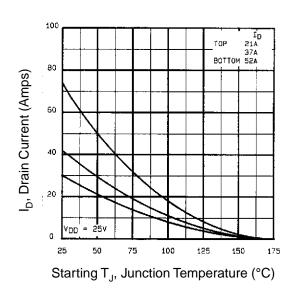
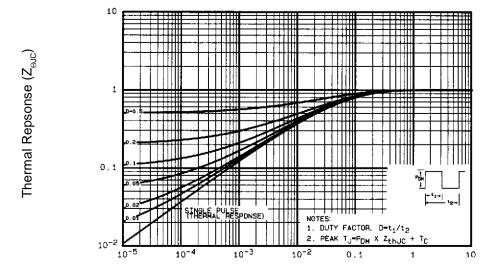


Fig. 12c Maximum Avalanche Energy vs. Drain Current

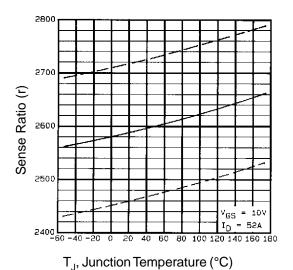


t₁, Rectiangular Pulse Duration (seconds)

Fig. 11 Maximum Effective Transient Thermal Impedance, Junction-to-Case

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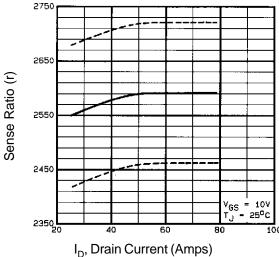


Fig. 15 Typical HEXSense Ratio vs.

Junction Temperature

2900 = 25°C 52A 2800 Sense Ratio (r) 2700 2600 2500 V_{GS}, Gate-to-Source Voltage (Volts)

Fig. 17 Typical HEXSense Ratio vs. **Gate Voltage**

Mechanical drawings, Appendix A Part marking information, Appendix B Test Circuit diagrams, Appendix C

Fig. 16 Typical HEXSense Ratio vs. **Drain Current**

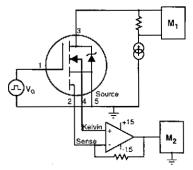


Fig. 18 HEXSense Ratio Test Circuit

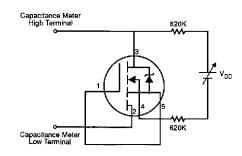


Fig. 19 HEXSense Sensing Cell Output **Capacitance Test Circuit**

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